

Citations for Target : **Ta2O5**

Pub. Year	Authors, Title, Journal Citation and Comments	Citation Num
1973	Behrisch, R. Schertzer, B. M. U. 'Rutherford Backscattering as a Tool to Determine Electronic Stopping Powers in Solids' <i>Thin Solid Films, 19, 247-257 (1973)</i> <i>Comment : S. 50-150 keV H -> Nb, Ta, Ta2O5</i>	1973-Behr 0508
1973	Phillips, D. Pringle, J. P. S. 'Surface Effects in the Measurement of Range Profiles by Oxide Dissolution' <i>J. Electrochem. Soc., 120, 1067-66 (1973)</i> <i>Comment : R, dR. 5, 40 keV Tl, Au -> Ta2O5</i>	1973-Phil 0686
1974	Pringle, J. P. S. 'Range Profiles for Ions Implanted into Anodic Tantalum Oxide' <i>J. Electrochem. Soc., 121, 45-55 (1974)</i> <i>Comment : R. 0.5-160 keV 24Na, 42K, 86Rb, 125Xe, 134Cs, 204Tl, 222Rn -> Ta2O5</i>	1974-Prin2 0228
1976	Bottiger, J. Rud, J. R. Leslie and N. 'Range Profiles of 6-16-keV Hydrogen Ions Implanted in Metal Oxides' <i>J. Appl. Phys., 47, 1672-75 (1976)</i> <i>Comment : R, dR. 6-16 keV H -> Al2O3, Nb2O5, Ta2O5</i>	1976-Bott2 0797
1976	Pringle, J. P. S. 'A Comparison of Sectioning Methods used to Measure Concentration Profiles in Anodic Oxides' <i>Can. J. Phys., 54, 56-65 (1976)</i> <i>Comment : R. dR. (10-160 keV) Na, Ar, K, Kr, Xe -> Al2O3, Ta2O5, WO3, Ta2O5</i>	1976-Prin 0819
1976	Schertzer, B. M. U. Borgesen, P. Nicolet, M. -A. Mayer, J. W. 'Determination of Stopping Cross Sections by Rutherford Backscattering' <i>O. Meyer, G. Linker, F. Kappeler (Ed.): Ion Beam Surface Layer Analysis. Plenum, N. Y., 33-46 (1976)</i> <i>Comment : S. 0.2-2.0 MeV He -> Au, Pt, Ta2O5, SiO2</i>	1976-Sche 0786
1978	Moller, W. 'Background Reduction in D(3He,alpha)H Depth Profiling Experiments using a Simple Electrostatic Deflector' <i>Nucl. Inst. Methods, 157, 223-227 (1978)</i> <i>Comment : R, dR. 20 keV D -> Al2O3, Ta2O5</i>	1978-Moll 1163
1978	Stephens, K. G. Wilson, I. H. 'Properties and Applications of Ion-Implanted Films' <i>Thin Solid Films, 50, 325-347 (1978)</i> <i>Comment : R. 30 keV O -> Ta2O5, 60-80 keV Ar -> Ta</i>	1978-Step 1242

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1979	Ishii, K. Blondiaux, G. Valladon, M. Debrun, D. L. 'The Study of Stopping Powers by the Method of the Average Stopping Power' <i>Nucl. Inst. Methods, 158, 199-203 (1979)</i> <i>Comment : S, T (3MeV) -> BeO, Al2O3, SiO2, TiO2, ZnO, Nb2O5, Ta2O5</i>	1979-Ishi 1539
1980	Blondiaux, G. Valladon, M. Ishii, K. Debrun, J. L. 'Search for the Influence of Chemical Effect on the Stopping Power: the Case of Oxides' <i>Nucl. Inst. Methods, 168, 29-31 (1980)</i> <i>Comment : S, dS. .5-2.5 MeV H -> BeO, Al2O3, TiO2, Zno, Nb2O5, Ta2O5</i>	1980-Blon 1314
1983	Hautala, M. Paltemaa, R. Anttila, A. Luomajarvi, M. 'Ion Range Distributions in Oxides' <i>Nucl. Inst. Methods, 209/210, 37-41 (1983)</i> <i>Comment : R. N(20-100 keV) -> SiO2, MoO3, Ta2O5</i>	1983-Haut 2020
1997	Moon, D. W. Kim, H. K. Kim, Y. P. Ha, Y. H. Choi, S. K. 'The Electronic Energy Loss of 100 keV Heavy Ions in Medium Energy Ion Scattering Analysis of Ta2O5 Ultrathin Film' <i>Nucl. Inst. Methods, B125, 120-123 (1997)</i> <i>Comment : S, Li, N, Ne (100 keV) -> Ta2O5</i>	1997-Moon 2238